

Integrated circuits - Measurement of electromagnetic
emissions - Part 4: Measurement of conducted
emissions - 1 Ω/150 Ω direct coupling method

ESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

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and corrigenda (if any)

English Version

Integrated circuits - Measurement of electromagnetic emissions
- Part 4: Measurement of conducted emissions - 1 Ω/150 Ω
direct coupling method
(IEC 61967-4:2021)

Circuits intégrés - Mesure des émissions
électromagnétiques - Partie 4: Mesure des émissions
conduites - Méthode par couplage direct 1 Ω/150 Ω
(IEC 61967-4:2021)

Integrierte Schaltungen - Messung von
elektromagnetischen Aussendungen - Teil 4: Messung der
leitungsgeführten Aussendungen - Messung mit direkter 1-
Ohm-/150-Ohm-Kopplung
(IEC 61967-4:2021)

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European foreword

The text of document 47A/1101/CDV, future edition 2 of IEC 61967-4, prepared by SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61967-4:2021.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2022-01-20
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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

CISPR 16-1-2 NOTE Harmonized as EN 55016-1-2

CISPR 25 NOTE Harmonized as EN 55025

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61000-4-6	-	Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields	EN 61000-4-6	-
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions - Part 1: General conditions and definitions	EN IEC 61967-1	-

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Integrated circuits – Measurement of electromagnetic emissions –
Part 4: Measurement of conducted emissions – 1 Ω/150 Ω direct coupling
method**

**Circuits intégrés – Mesure des émissions électromagnétiques –
Partie 4: Mesure des émissions conduites – Méthode par couplage direct
1 Ω/150 Ω**





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Edition 2.0 2021-03

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Integrated circuits – Measurement of electromagnetic emissions –
Part 4: Measurement of conducted emissions – 1 Ω/150 Ω direct coupling
method**

**Circuits intégrés – Mesure des émissions électromagnétiques –
Partie 4: Mesure des émissions conduites – Méthode par couplage direct
1 Ω/150 Ω**

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CONTENTS

FOREWORD	5
1 Scope	7
2 Normative references	7
3 Terms and definitions	7
4 General	7
4.1 Measurement basics	7
4.2 RF current measurement	9
4.3 RF voltage measurement at IC pins	9
4.4 Assessment of the measurement technique	9
5 Test conditions	9
6 Test equipment	10
6.1 RF measuring instrument	10
6.2 RF current probe specification	10
6.3 Test of the RF current probe capability	11
6.4 Matching network specification	11
7 Test setup	12
7.1 General test configuration	12
7.2 Printed circuit test board layout	12
8 Test procedure	13
9 Test report	13
Annex A (informative) Probe verification procedure	14
Annex B (informative) Classification of conducted emission levels	18
B.1 Introductory remark	18
B.2 General	18
B.3 Definition of emission levels	18
B.4 Presentation of results	18
B.4.1 General	18
B.4.2 Examples	20
Annex C (informative) Example of reference levels for automotive applications	22
C.1 Introductory remark	22
C.2 General	22
C.3 Reference levels	22
C.3.1 General	22
C.3.2 Measurements of conducted emissions, 1 Ω method	23
C.3.3 Measurements of conducted emissions, 150 Ω method	23
Annex D (informative) EMC requirements and how to use EMC IC measurement techniques	24
D.1 Introductory remark	24
D.2 Using EMC measurement procedures	24
D.3 Assessment of the IC influence to the EMC behaviour of the modules	24
Annex E (informative) Example of a test setup consisting of an EMC main test board and an EME IC test board	26
E.1 Introductory remark	26
E.2 EMC main test board	26
E.3 EME IC test board	28

E.3.1	General explanation of the test board	28
E.3.2	How to build the test system	28
E.3.3	PCB layout and component positioning.....	30
Annex F (informative)	150 Ω direct coupling networks for common mode emission measurements of differential mode data transfer ICs and similar circuits	32
F.1	Basic direct coupling network.....	32
F.2	Example of a common-mode coupling network alternative for LVDS or RS485 or similar systems	33
F.3	Example of a common-mode coupling network alternative for differential IC outputs to resistive loads (e.g. airbag ignition driver)	34
F.4	Example of a common-mode coupling network for CAN systems	34
Annex G (informative)	Measurement of conducted emissions in extended frequency range.....	35
G.1	General.....	35
G.2	Guidelines	35
G.2.1	Measurement network	35
G.2.2	Network components	36
G.2.3	Network layout.....	38
G.2.4	Network verification	38
G.2.5	Test board	39
G.3	Application area	41
Bibliography	43
Figure 1	– Example of two emitting loops returning to the IC via common ground	8
Figure 2	– Example of IC with two ground pins, a small I/O loop and two emitting loops	8
Figure 3	– Construction of the 1 Ω RF current probe	10
Figure 4	– Impedance matching network corresponding with IEC 61000-4-6	12
Figure 5	– General test configuration	12
Figure A.1	– Test circuit.....	14
Figure A.2	– Insertion loss of the 1 Ω probe	14
Figure A.3	– Layout of the verification test circuit.....	15
Figure A.4	– Connection of the verification test circuit.....	16
Figure A.5	– Minimum decoupling limit versus frequency	16
Figure A.6	– Example of 1 Ω probe input impedance characteristic	17
Figure B.1	– Emission level scheme.....	19
Figure B.2	– Example of the maximum emission level G8f	20
Figure C.1	– 1 Ω method – Examples of reference levels for conducted disturbances from semiconductors (peak detector)	23
Figure C.2	– 150 Ω method – Examples of reference levels for conducted disturbances from semiconductors (peak detector)	23
Figure E.1	– EMC main test board	27
Figure E.2	– Jumper field.....	27
Figure E.3	– EME IC test board (contact areas for the spring connector pins of the main test board).....	28
Figure E.4	– Example of an EME IC test system	29
Figure E.5	– Component side of the EME IC test board	30
Figure E.6	– Bottom side of the EME IC test board	31

Figure F.1 – Basic direct coupling for common mode EMC measurements	32
Figure F.2 – Measurement setup for the S21 measurement of the common-mode coupling	33
Figure F.3 – Using split load termination as coupling for measuring equipment	33
Figure F.4 – Using split load termination as coupling for measuring equipment	34
Figure F.5 – Example of an acceptable adaptation for special network requirements (e.g. for CAN systems)	34
Figure G.1 – Example of a $150\ \Omega$ measurement network	36
Figure G.2 – Example of RF characteristic of network components	37
Figure G.3 – Examples of S21 characteristic by simulation	39
Figure G.4 – Examples of test board section	40
Figure G.5 – Examples of unwanted cross coupling between measurement network and traces on test PCB	40
Figure G.6 – Examples of unwanted signal line cross coupling on S21 transfer characteristic of RF measurement network	40
Figure G.7 – Examples of test board with additional signal line connected to IC pin	41
Figure G.8 – Examples of stub lines length effects on S21 transfer characteristic of RF measurement network	41
Table 1 – Specification of the RF current probe	11
Table 2 – Characteristics of the impedance matching network	12
Table B.1 – Emission levels	21
Table D.1 – Examples in which the measurement procedure can be reduced	24
Table D.2 – System- and module-related ambient parameters	25
Table D.3 – Changes at the IC which influence the EMC	25
Table G.1 – Draft selection table for conducted emission measurements at pins above 1 GHz	42

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**INTEGRATED CIRCUITS –
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1 Ω/150 Ω direct coupling method****FOREWORD**

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This second edition cancels and replaces the first edition published in 2002 and Amendment 1:2006. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) frequency range of 150 kHz to 1 GHz has been deleted from the title;
- b) recommended frequency range for 1 Ω method has been reduced to 30 MHz;
- c) Annex G with recommendations and guidelines for frequency range extension beyond 1 GHz has been added.

The text of this International Standard is based on the following documents:

Draft	Report on voting
47A/1101/CDV	47A/1107/RVC

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

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